

Notice of References Cited	Application/Control No. 10/767,851	Applicant(s)/Patent Under Reexamination KUTURIANU ET AL.	
	Examiner Ben C. Wang	Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,000,224 b1	02-2006	Osborne et al.	717/125
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Farchi et al., Using a model-based test generator to test for standard conformance, IBM Systems Journal, VOL 41, NO 1, 2002, Pages 89-110
	V	Hartman et al., AGEDIS - Architecture, Interfaces & Tools, IBM Haifa Labs, December 11, 2003, Pages 1-35
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.